

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10786158	BEAN ET AL.
	Examiner	Art Unit
	Chin-Shue, Alvin C	3634

SEARCHED

Class	Subclass	Date	Examiner
update		5/19/07	acs
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SEARCH NOTES

Search Notes	Date	Examiner

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner